

OptiMOS[™]- 6 Power-Transistor





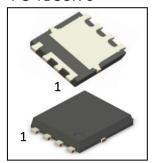
Product Summary

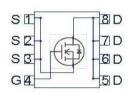
V_{DS}	40	V
R _{DS(on),max}	2.5	mΩ
I _D	100	Α

Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Logic Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

PG-TDSON-8





Туре	Package	Marking
IAUC100N04S6L025	PG-TDSON-8	6N04L025

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25°C, V _{GS} =10V	100	А
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{2)}$	83	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	400	
Avalanche energy, single pulse ²⁾	E _{AS}	$I_{\rm D}$ =20A, $R_{\rm G,min}$ =25 Ω	85	mJ
Avalanche current, single pulse	I _{AS}	$R_{\rm G,min}$ =25 Ω	20	А
Gate source voltage	V_{GS}	-	±16	V
Power dissipation	P_{tot}	T _C =25°C	62	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 + 175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	2.4	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm ² cooling area ³⁾	1	-	50	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS} = 0$ V, $I_{\rm D} = 1$ mA		ı	ı	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=24\mu{\rm A}$	1.2	1.6	2.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	1	1	1	μA
		$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	-	6	
Gate-source leakage current	I _{GSS}	V _{GS} =16V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =4.5V, I _D =50A	-	2.90	3.60	mΩ
		V _{GS} =10V, I _D =50A	-	2.06	2.56	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	1553	2019	pF
Output capacitance	Coss	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =25V, f =1MHz	-	435	566	1
Reverse transfer capacitance	C_{rss}		-	28	42	
Turn-on delay time	t _{d(on)}		-	3	-	ns
Rise time	t_{r}	V _{DD} =20V, V _{GS} =10V,	-	2	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =100A, $R_{\rm G}$ =3.5 Ω	-	14	-	
Fall time	t _f]	-	7	-	
Gate Charge Characteristics ²⁾			T	T	ı	1
Gate to source charge	Q _{gs}		-	5.0	6.7	nC
Gate to drain charge	Q_{gd}	V _{DD} =32V, I _D =100A,	-	5.1	7.6	\prod
Gate charge total	Qg	V _{GS} =0 to 10V	-	25	34	
Gate plateau voltage	V _{plateau}		-	3.2	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T 0500	-	-	100	А
Diode pulse current ²⁾	I _{S,pulse}	-T _C =25°C	-	-	400	1
Diode forward voltage	V _{SD}	V _{GS} =0V, I _F =50A, T _j =25°C	-	0.8	1.1	V
Reverse recovery time ²⁾	t _{rr}	V_R =20V, I_F =50A, di_F/dt =100A/ μ s	-	28	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	16	-	nC

¹⁾ Current is limited by package; with an $R_{\rm thJC}$ = 2.4 K/W the chip is able to carry 117 A at 25°C.

²⁾ The parameter is not subject to production test- verified by design/characterization.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10 \text{ V}$$

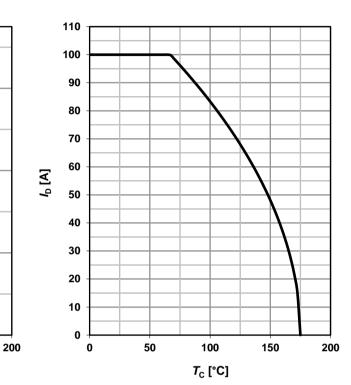
100

*T*_C [°C]

150

2 Drain current

$$I_{\rm D} = f(T_{\rm C}); \ V_{\rm GS} = 10 \ {\rm V}$$



3 Safe operating area

$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

50

parameter: t_p

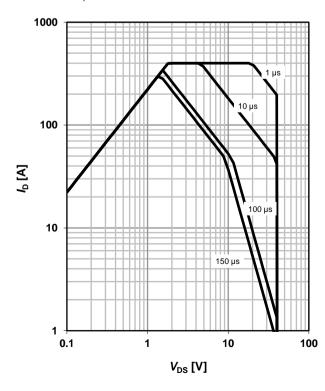
0

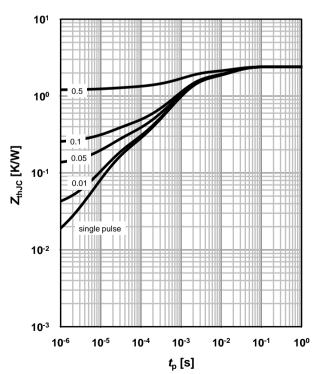
0

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter: $D=t_p/T$



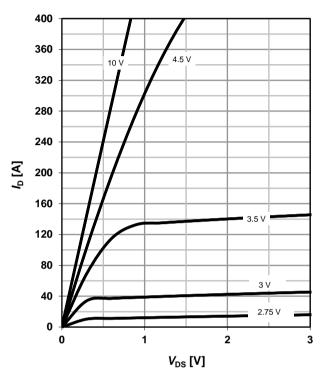




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

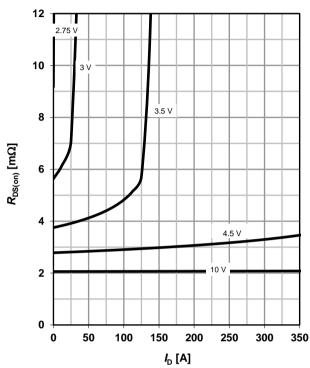
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

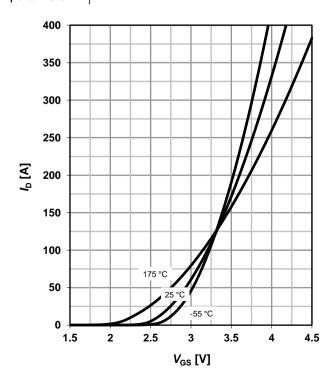
parameter: V_{GS}



7 Typ. transfer characteristics

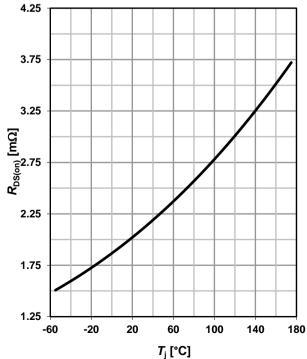
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: $T_{\rm j}$



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 50 \text{ A}; V_{GS} = 10 \text{ V}$$





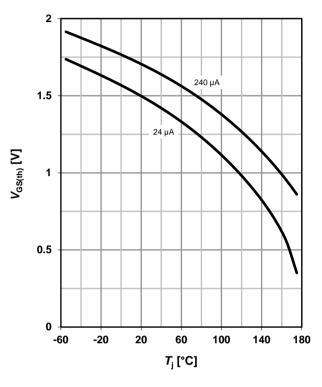
9 Typ. gate threshold voltage

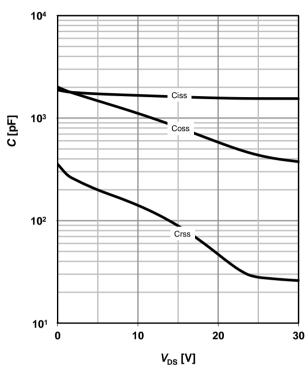
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

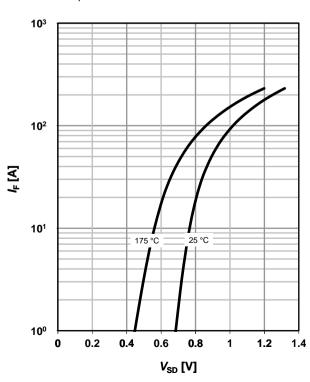
 $IF = f(V_{SD})$

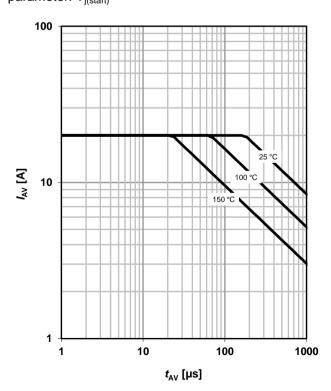
parameter: $T_{\rm j}$

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}





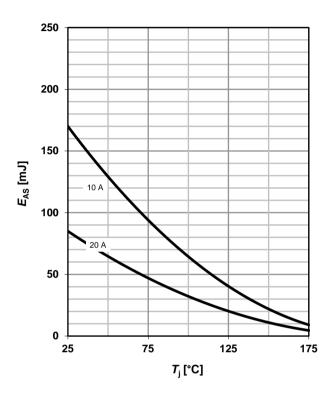


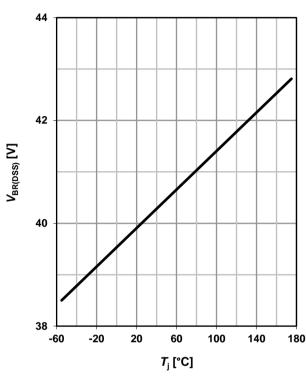
13 Avalanche energy

$E_{AS} = f(T_i)$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$$

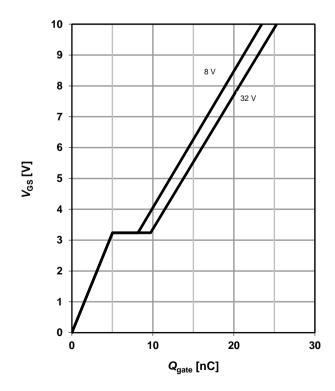




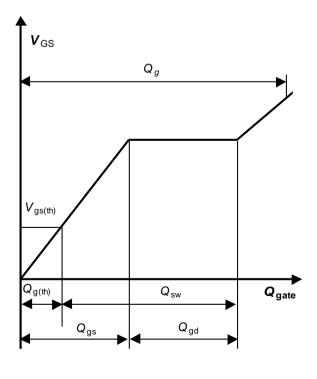
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 100 A pulsed$

parameter: V_{DD}



16 Gate charge waveforms





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Revision History

Version	Date	Changes